

Notice of References Cited	Application/Control No. 10/050,764		Applicant(s)/Patent Under Reexamination WALLS ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,500,941 A	03-1996	Gil, Luis	714/38
*	B	US-5,699,507 A	12-1997	Goodnow et al.	714/38
*	C	US-5,850,516 A	12-1998	Schneier, Bruce	726/25
*	D	US-5,854,924 A	12-1998	Rickel et al.	717/132
*	E	US-5,922,079 A	07-1999	Booth et al.	714/26
*	F	US-5,925,123 A	07-1999	Tremblay et al.	712/212
*	G	US-5,970,242 A	10-1999	O'Connor et al.	717/100
*	H	US-6,014,723 A	01-2000	Tremblay et al.	711/1
*	I	US-6,085,029 A	07-2000	Kolawa et al.	714/38
*	J	US-6,125,439 A	09-2000	Tremblay et al.	712/202
*	K	US-6,148,401 A	11-2000	Devanbu et al.	713/170
*	L	US-6,154,876 A	11-2000	Haley et al.	717/133
*	M	US-6,381,698 B1	04-2002	Devanbu et al.	713/170

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ghosh et al., An Approach for Certifying Security in Software Components, 1998, Proc. 21st {NIST}-{NCSC} National Information Systems Security Conference, <citeseer.ist.psu.edu/104720.html>
	V	Ghosh, A.K.; O'Connor, T.; McGraw, G., An automated approach for identifying potential vulnerabilities in software, 1998, Security and Privacy, 1998. Proceedings. 1998 IEEE Symposium on, 3-6 May 1998 Page(s):104 - 114
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/050,764		Applicant(s)/Patent Under Reexamination WALLS ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,850,516 A	12-1998	Schneier, Bruce	726/25
*	B	US-2002/0026591 A1	02-2002	Hartley et al.	713/201
*	C	US-6,427,232 B1	07-2002	Ku et al.	717/124
*	D	US-6,473,896 B1	10-2002	Hicken et al.	717/132
*	E	US-6,513,154 B1	01-2003	Porterfield, John R.	717/101
*	F	US-6,578,094 B1	06-2003	Moudgill, Mayan	710/57
*	G	US-6,584,569 B2	06-2003	Reshef et al.	726/25
*	H	US-2003/0233581 A1	12-2003	Reshef et al.	713/201
*	I	US-2004/0006704 A1	01-2004	Dahlstrom et al.	713/200
*	J	US-6,718,485 B1	04-2004	Reiser, John F.	714/38
*	K	US-6,807,569 B1	10-2004	Bhimani et al.	709/217
*	L	US-6,862,696 B1	03-2005	Voas et al.	714/38
*	M	US-6,895,578 B1	05-2005	Kolawa et al.	717/130

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	D. Wagner, J. Foster, E. Brewer, and A. Aiken. A first step towards automated detection of buffer overrun vulnerabilities. In Network and Distributed System Security Symposium, San Diego, CA, February 2000.
*	V	Necula et al., The design and implementation of a certifying compiler, 1998, ACM, pp 333-344.
*	W	Bush et al., A static analyzer for finding dynamic programming errors, 2000, Software Practice and Experience, pp 775-802.
*	X	Viega, J.; Bloch, J.T.; Kohno, Y.; McGraw, G., ITS4: a static vulnerability scanner for C and C++ code, December 2000, IEEE, Page(s):257 - 267.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/050,764	Applicant(s)/Patent Under Reexamination WALLS ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,941,102 A	07-1990	Darnell et al.	706/60
*	B	US-5,133,045 A	07-1992	Gaither et al.	706/46
*	C	US-5,247,693 A	09-1993	Bristol, Edgar H.	717/139
*	D	US-5,293,629 A	03-1994	Conley et al.	717/154
*	E	US-5,581,696 A	12-1996	Kolawa et al.	714/38
*	F	US-5,761,408 A	06-1998	Kolawa et al.	714/38
*	G	US-5,784,553 A	07-1998	Kolawa et al.	714/38
*	H	US-5,842,019 A	11-1998	Kolawa et al.	717/130
*	I	US-5,850,516 A	12-1998	Schneier, Bruce	726/25
*	J	US-5,860,011 A	01-1999	Kolawa et al.	717/142
*	K	US-2001/0013094 A1	08-2001	Etoh et al.	712/227
*	L	US-6,412,071 B1	06-2002	Hollander et al.	726/23
*	M	US-6,806,893 B1	10-2004	Kolawa et al.	715/848

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,924,408 A	05-1990	Highland, Frederic D.	706/60
*	B	US-5,132,972 A	07-1992	Hansen, Robert G.	714/38
*	C	US-5,850,516 A1	12-1998	Schneier, Bruce	726/25
*	D	US-2004/0103315 A1	05-2004	Cooper et al.	713/201
	E	US-			
	F	US-			
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	H	US-			
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